

**Search Notes**

Application/Control No.

10/767,763

Examiner

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Applicant(s)/Patent under  
Reexamination

OGAWA, HIDEHIKO

Art Unit

2625

**SEARCHED**

Class	Subclass	Date	Examiner
358	1.15, 402, 440	2/22/2007	TDL
379	100.01	2/22/2007	TDL
379	100.08	2/22/2007	TDL
379	100.13	2/22/2007	TDL
379	100.17	2/22/2007	TDL

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner